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|-----------------------------------|--|-----------------------------|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination LEE ET AL. | |
| | | Examiner David J. Makiya | Art Unit 2885 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-4,769,345 A | 09-1988 | Butt et al. | 29/827 |
| * | B | US-2002/0153835 A1 | 10-2002 | Fujiwara et al. | 313/512 |
| * | C | US-2003/0219919 A1 | 11-2003 | Wang et al. | 438/26 |
| * | D | US-2006/0268579 A1 | 11-2006 | Han et al. | 362/629 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|--------------|----------------|
| | N | JP 09045965 A | 02-1997 | Japan | IZUNO et al. | H01L 33/00 |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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